## Test Report issued under the responsibility of:





## TEST REPORT IEC 60947-2

Low-voltage switchgear and controlgear. Part 2: Circuit-breakers

Date of issue...... 2016-10-14

CB Testing Laboratory...... Shanghai Testing & Inspection Tip at ute for Electrical Equipment

(STIEE)

Address ...... 505 Wu Ning Rd. Shanghai 200063, P.R. CHINA

Applicant's name ...... Zhejiang Tengen Electrics Co., Ltd.

Address ...... TENGEN Industry Zone, Liushi, Yueqing City, Zhejiang

Province, P.R. China

**Test specification:** 

Test procedure .....: CB scheme

Non-standard test method.....: N/A

Test Report Form No...... IEC60947\_2G

Test Report Form(s) Originator ......: DEKRA Certification BV

Master TRF ...... Dated 2013-11

Copyright © 2013 IEC System for Conformity Testing and Certification of Electrical Equipment (IECEE), Geneva, Switzerland. All rights reserved.

This publication may be reproduced in whole or in part for non-commercial purposes as long as the IECEE is acknowledged as copyright owner and source of the material. IECEE takes no responsibility for and will not assume liability for damages resulting from the reader's interpretation of the reproduced material due to its placement and context.

If this Test Report Form is used by non-IECEE members, the IECEE/IEC logo and the reference to the CB Scheme procedure shall be removed.

This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.

Trade Mark .....: TENGEN

Manufacturer ...... Zhejiang Tengen Electrics Co., Ltd.

Model/Type reference...... TGB3Z-63, TGB3Z-63H

Ratings ...... Ue: AC230V(1P), AC400V(2P,3P,4P),

DC80V(1P appearance),DC125V(2P appearance)

In: 1, 2, 3, 4, 5, 6, 10, 16, 20, 25, 32, 40, 50, 63A

Testing procedure and testing location:						
⊠ CE	3 Testing Laboratory:	Shanghai Testing & Inspection Institute for Electrical Equipment (STIEE)				
Testing location/ address:		505 Wu Ning Rd. Shanghai 200063, P.R. CHINA				
Test	ed by (name + signature):	Cui Tao	在· 陆 魏 秋媛			
Арр	roved by (name + signature):	Wei Qingyuan	魏水媛			
L Te	sting procedure: TMP	N/A				
Testing location/ address:		N/A				
Test	ed by (name + signature):	N/A				
Арр	roved by (name + signature):	N/A				
		,.				
☐ Testing procedure: WMT		N/A				
Testing location/ address:		N/A				
Test	ed by (name + signature):	N/A				
Witn	nessed by (name + signature):	N/A				
Арр	roved by (name + signature):	N/A				
☐ Testing procedure: SMT		N/A				
Testing location/ address:		N/A				
Test	ed by (name + signature):	N/A				
Арр	roved by (name + signature):	N/A				
Sup	ervised by (name + signature):	N/A				

C		- 4	4 45	
Sum	mary	OT	testir	ıa:

In case of alternative test programs for circuit breakers with a different number of poles, the following program is used:

☐ Programme 1 (three pole fully tested)

☑ Programme 2 (four pole fully tested)

☐ Alternative program not applicable

## Tests performed (name of test and test clause 1/3):

Туре	Ue	In	Poles	Sequence
TGB3Z-63(D type)	AC400V	63A	4	I
TGB3Z-63(D type)	AC400V	63A	2	I <sup>1)</sup>
TGB3Z-63(D type)	AC230V	63A	1	J <sup>2)</sup>
TGB3Z-63(C type)	AC400V	63A	4	I
TGB3Z-63(C type)	AC400V	63A	2	I <sup>1)</sup>
TGB3Z-63(C type)	AC230V	63A	1	J <sup>2)</sup>
TGB3Z-63(B type)	AC400V	63A	4	I
TGB3Z-63(B type)	AC400V	63A	2	I <sup>1)</sup>
TGB3Z-63(B type)	AC230V	63A	1	J <sup>2)</sup>
TGB3Z-63(D type)	DC80V	63A	1P appearance	1
TGB3Z-63(C type)	DC80V	63A	1P appearance	I
TGB3Z-63(B type)	DC80V	63A	1P appearance	I
TGB3Z-63(D type)	DC125V	63A	2P appearance	I
TGB3Z-63(D type)	AC400V	63A	4	II
TGB3Z-63(D type)	AC400V	1A	4	II
TGB3Z-63H(D type)	AC400V	63A	4	II
TGB3Z-63H(D type)	AC400V	1A	4	II
TGB3Z-63H(D type)	DC80V	63A	1P appearance	II